

From the Editor

Monday, February 15, 2010



In 2010, the world's largest annual microscopy meeting and instrument exhibition, Microscopy & Microanalysis, will be held August 1–5 in Portland, Oregon. This delightful meeting location was the site for our successful 1999 M&M meeting, and we return to Portland by popular demand.

This is an extraordinary time for microscopy and microanalysis. At no time in my memory were there such exciting technical developments and new products: advanced methods in light microscopy, new applications of scanning probe microscopy, aberration-corrected EM, ultra-fast EM, focused ion-beam methods, atom probe tomography, silicon-drift x-ray detectors, and analytical data acquisition by spectrum imaging. As always, *the* place to hear about and see these developments is the M&M meeting.

Remember the Deadline! Extended abstracts for platform and poster presentations are due by **Monday, February 15th, 2010**. This hard deadline is necessary in order to produce a complete compilation of extended abstracts in time for the meeting. This year all abstracts will be on a DVD-ROM provided to each full-meeting registrant. While shorter abstracts are allowed, the opportunity to lay out a summary of your presentation in the traditional Microscopy & Microanalysis two-page abstract format with color figures, graphs, and diagrams on the second page is a distinct advantage.

To view the broad range of topics for the 34 special symposia, go to the MSA website, <http://www.microscopy.org>, and find the M&M2010 button. This leads you to the meeting site where you can locate all you need to know about the meeting: the Call for Papers, submission details, registration and hotel information, and fun things to do in and around Portland. The opening plenary presentation, "What Microscopy Can Tell Us about Alzheimer's and Related Diseases," will be given by Professor Mark Welland of the Nanoscience Centre at the University of Cambridge in the UK. This talk will highlight the use of scanned probe microscopies to fight disease.

If you can't find what you need on the website, contact the program chair, John Mansfield (jfmjfm@umich.edu), and he will do his best to help you. John Mansfield describes additional features of M&M 2010 on page 38. Plan now to attend this important meeting. Don't miss it.

Charles Lyman
Editor-in-Chief

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